

Notice of References Cited

Application/Control No.

10/606,900

Applicant(s)/Patent Under
Reexamination
HAMAKAWA ET AL.

Examiner

G. Nagesh Rao

Art Unit

1722

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,362,494	03-2002	Yagi, Shigeru	257/76
*	B	US-6,706,959	03-2004	Hamakawa et al.	136/250
*	C	US-2006/0183625	08-2006	Miyahara, Kenichiro	501/098.4
*	D	US-7,196,262	03-2007	Gronet, Chris M	136/246
*	E	US-2002/0096206	07-2002	Hamakawa et al.	136/244
*	F	US-2002/0162585	11-2002	Sugawara et al.	136/250
*	G	US-6,563,041	05-2003	Sugawara et al.	136/250
*	H	US-6,437,234	08-2002	Kyoda et al.	136/250
*	I	US-6,355,873	03-2002	Ishikawa, Akira	136/250
*	J	US-6,319,314	11-2001	Shoei, Kurosaka	117/206
*	K	US-6,221,165	04-2001	Zhang et al.	118/723R
*	L	US-5,183,493	02-1993	Brandau et al.	75/335
*	M	US-3,998,659	12-1976	Wakefield, Gene Felix	136/250

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO99/22048	06-1999	JAPAN	Nakata, Josuke	C30B 30/08
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.